

# SNx4HC112 Dual J-K Negative-Edge-Triggered Flip-Flops With Clear and Preset

## 1 Features

- Wide operating voltage range of 2V to 6V
- Outputs can drive up to 10 LSTTL loads
- Low power consumption, 40 $\mu$ A max  $I_{CC}$
- Typical  $t_{pd} = 13\text{ns}$
- $\pm 4\text{mA}$  output drive at 5V
- Low input current of 1 $\mu$ A max

## 2 Applications

- Servers
- LED displays
- Network switch
- Telecom infrastructure
- Motor drivers
- I/O expanders

## 3 Description

The SNx4HC112 devices contain two independent J-K negative-edge-triggered flip-flops. A low level at the preset ( $\overline{PRE}$ ) or clear ( $\overline{CLR}$ ) inputs sets or resets the outputs, regardless of the levels of the other inputs. When  $\overline{PRE}$  and  $\overline{CLR}$  are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock (CLK) pulse. Clock triggering occurs at a voltage level and is not directly related to the fall time of the CLK pulse. Following the hold-time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops perform as toggle flip-flops by tying J and K high.

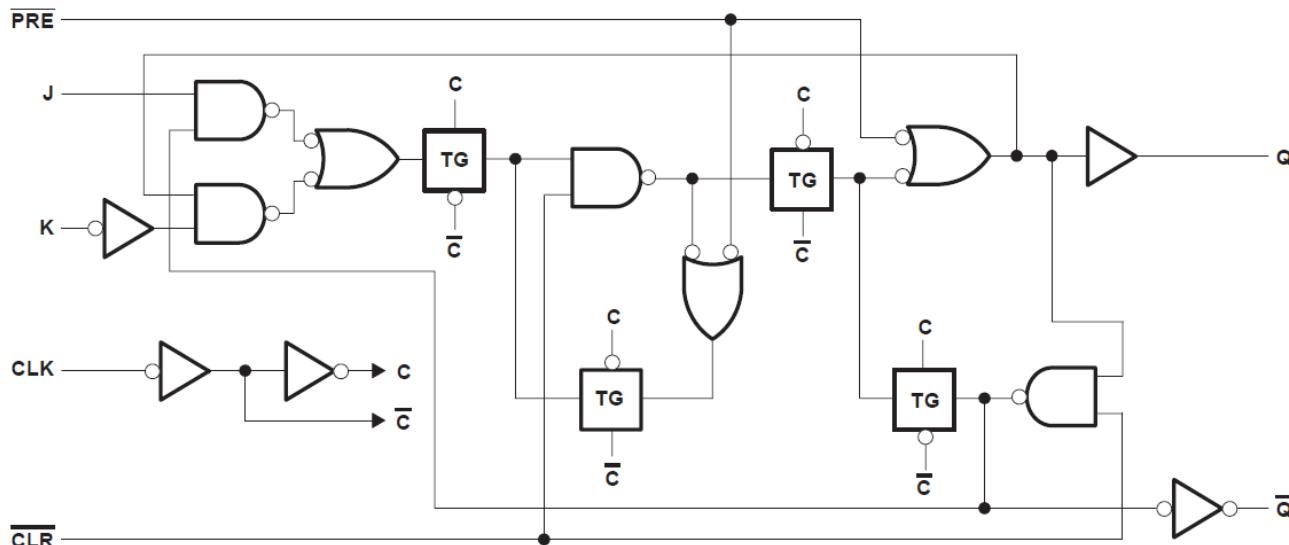
### Device Information

PART NUMBER	PACKAGE <sup>(1)</sup>	PACKAGE SIZE <sup>(2)</sup>	BODY SIZE (NOM) <sup>(3)</sup>
SNx4HC112	J (CDIP, 16)	19.56mm × 6.92mm	19.56mm × 6.92mm
	D (SOIC, 16)	9.9mm × 6mm	9.9mm × 3.9mm
	N (PDIP, 16)	19.3mm × 9.4mm	19.3mm × 6.35mm
	FK (LCCC, 20)	8.89mm × 8.89mm	8.89mm × 8.89mm
	W (CFP, 16)	10.3mm × 6.73mm	10.3mm × 6.73mm

(1) For more information, see [Section 11](#)

(2) The package size (length × width) is a nominal value and includes pins, where applicable.

(3) The body size (length × width) is a nominal value and does not include pins.



Functional Block Diagram

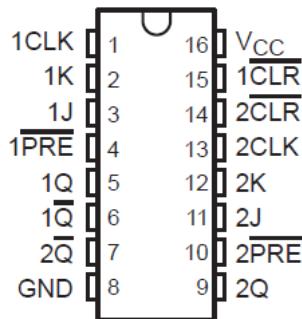


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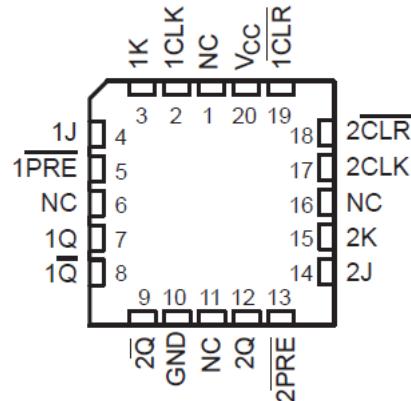
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## 4 Pin Configuration and Functions



**Figure 4-1. J, D, N, W Package,  
16-Pin CDIP, SOIC, PDIP, CFP  
(Top View)**



NC – No internal connection

**Figure 4-2. FK Package,  
20-Pin LCCC  
(Top View)**

## 5 Specifications

### 5.1 Absolute Maximum Ratings

over operating free-air temperature range<sup>(1)</sup>

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range		-0.5	7	V
I <sub>IK</sub>	Input clamp current <sup>(2)</sup>	V <sub>I</sub> < 0 or V <sub>I</sub> > V <sub>CC</sub>		±20	mA
I <sub>OK</sub>	Output clamp current <sup>(2)</sup>	V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub>		±20	mA
I <sub>O</sub>	Continuous output current	V <sub>O</sub> = 0 to V <sub>CC</sub>		±25	mA
	Continuous current through V <sub>CC</sub> or GND			±50	mA
T <sub>J</sub>	Junction temperature			150	°C
T <sub>stg</sub>	Storage temperature range		-65	150	°C

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

### 5.2 Recommended Operating Conditions<sup>(2)</sup>

		SN54HC112			SN74HC112			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage	2	5	6	2	5	6	V
V <sub>IH</sub>	High-level input voltage	V <sub>CC</sub> = 2V	1.5		1.5			V
		V <sub>CC</sub> = 4.5V	3.15		3.15			
		V <sub>CC</sub> = 6V	4.2		4.2			
V <sub>IL</sub>	Low-level input voltage	V <sub>CC</sub> = 2V		0.5		0.5		V
		V <sub>CC</sub> = 4.5V		1.35		1.35		
		V <sub>CC</sub> = 6V		1.8		1.8		
V <sub>I</sub>	Input voltage	0	V <sub>CC</sub>	0	V <sub>CC</sub>	0	V <sub>CC</sub>	V
V <sub>O</sub>	Output voltage	0	V <sub>CC</sub>	0	V <sub>CC</sub>	0	V <sub>CC</sub>	V
t <sub>t</sub> <sup>(1)</sup>	Input transition (rise and fall) time	V <sub>CC</sub> = 2V		1000		1000		ns
		V <sub>CC</sub> = 4.5V		500		500		
		V <sub>CC</sub> = 6V		400		400		
T <sub>A</sub>	Operating free-air temperature	-55		125	-40		85	°C

(1) If this device is used in the threshold region (from V<sub>ILmax</sub> = 0.5V to V<sub>IHmin</sub> = 1.5V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at t<sub>t</sub> = 1000ns and V<sub>CC</sub> = 2V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.

(2) All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number [SCBA004](#).

### 5.3 Thermal Information

THERMAL METRIC		D (SOIC)		N (PDIP)		UNIT
		16 PINS		16 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance <sup>(1)</sup>	117.2		89.1		°C/W
$R_{\theta JC(\text{top})}$	Junction-to-case (top) thermal resistance	77.2		46.9		°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	75.6		47.4		°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	38.1		11.8		°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter	75.3		47		°C/W
$R_{\theta JC(\text{bot})}$	Junction-to-case (bottom) thermal resistance	N/A		N/A		°C/W

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC package thermal metrics](#) application report.

### 5.4 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V <sub>CC</sub>	T <sub>A</sub> = 25°C			SN54HC112		SN74HC112		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V <sub>OH</sub>	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -20µA	2V	1.9	1.998	1.9		1.9		V
			4.5V	4.4	4.499	4.4		4.4		
			6V	5.9	5.999	5.9		5.9		
		I <sub>OH</sub> = -4mA	4.5V	3.98	4.3		3.7		3.84	
		I <sub>OH</sub> = -5.2mA	6V	5.48	5.8		5.2		5.34	
V <sub>OL</sub>	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 20µA	2V	0.002	0.1	0.1		0.1		V
			4.5V	0.001	0.1	0.1		0.1		
			6V	0.001	0.1	0.1		0.1		
		I <sub>OL</sub> = 4mA	4.5V	0.17	0.26	0.4		0.33		
		I <sub>OL</sub> = 5.2mA	6V	0.15	0.26	0.4		0.33		
I <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or 0	6V		±0.1	±100	±1000		±1000		nA
I <sub>CC</sub>	V <sub>I</sub> = V <sub>CC</sub> or 0, I <sub>O</sub> = 0	6V			4	80		40		µA
C <sub>i</sub>		2V to 6V		3	10	10		10		pF

### 5.5 Timing Requirements

over recommended operating free-air temperature range (unless otherwise noted)

		V <sub>CC</sub>	T <sub>A</sub> = 25°C		SN54HC112		SN74HC112		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>clock</sub>	Clock frequency	2V	5		3.4		4		MHz
		4.5V	25		17		20		
		6V	29		20		24		
t <sub>w</sub>	Pulse duration	PRE or CLR low	2V	100	150		125		ns
			4.5V	20	30		25		
			6V	17	25		21		
		CLK high or low	2V	100	150		125		
			4.5V	20	30		25		
			6V	17	25		21		

## 5.5 Timing Requirements (continued)

over recommended operating free-air temperature range (unless otherwise noted)

			V <sub>cc</sub>	T <sub>A</sub> = 25°C		SN54HC112		SN74HC112		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>su</sub>	Setup time before CLK↓	Data (J, K)	2V	100		150		125		ns
			4.5V	20		30		25		
			6V	17		25		21		
		PRE or CLR inactive	2V	100		150		125		ns
			4.5V	20		30		25		
			6V	17		25		21		
t <sub>h</sub>	Hold time, data after CLK↓	2V	0		0	0		0		ns
		4.5V	0		0	0		0		
		6V	0		0	0		0		

## 5.6 Switching Characteristics

over recommended operating free-air temperature range, C<sub>L</sub> = 50 pF (unless otherwise noted) (see [Parameter Measurement Information](#))

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>cc</sub>	T <sub>A</sub> = 25°C			SN54HC112		SN74HC112		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f <sub>max</sub>			2V	5	10		3.4		4		MHz
			4.5V	25	50		17		20		
			6V	29	60		20		24		
t <sub>pd</sub>	PRE or CLR	Q or $\bar{Q}$	2V		54	165		245		205	ns
			4.5V		16	33		49		41	
			6V		13	28		42		35	
	CLK	Q or $\bar{Q}$	2V		56	125		185		155	
			4.5V		16	25		37		31	
			6V		13	21		31		26	
t <sub>t</sub>		Q or $\bar{Q}$	2V		29	75		110		95	ns
			4.5V		9	15		22		19	
			6V		8	13		19		16	

## 5.7 Operating Characteristics

T<sub>A</sub> = 25°C

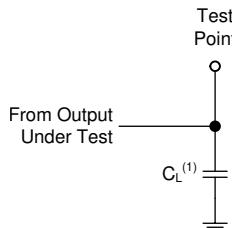
PARAMETER		TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	No load	35	pF

## 6 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1MHz,  $Z_O = 50\Omega$ ,  $t_t < 6\text{ns}$ .

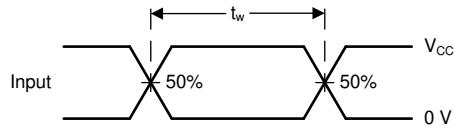
For clock inputs,  $f_{\text{max}}$  is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.

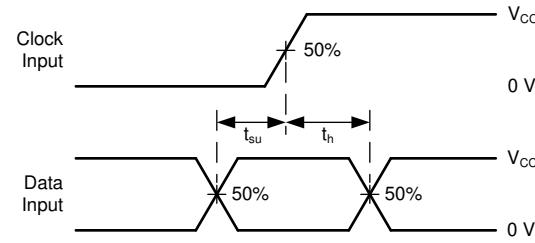


(1)  $C_L$  includes probe and test-fixture capacitance.

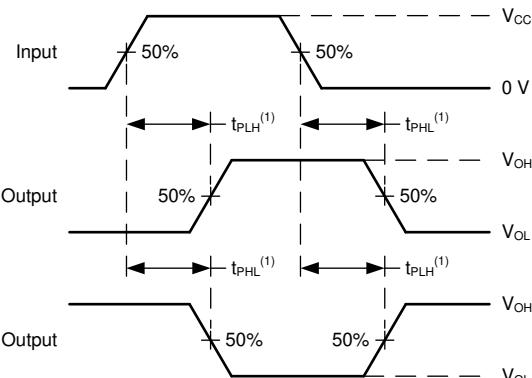
**Figure 6-1. Load Circuit for Push-Pull Outputs**



**Figure 6-2. Voltage Waveforms, Standard CMOS Inputs Pulse Duration**

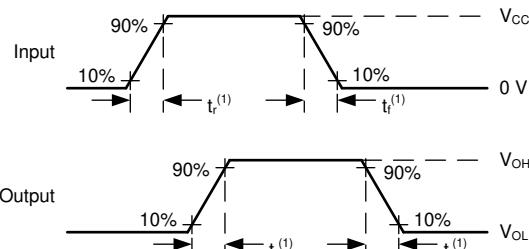


**Figure 6-3. Voltage Waveforms, Standard CMOS Inputs Setup and Hold Times**



(1) The greater between  $t_{PLH}$  and  $t_{PHL}$  is the same as  $t_{pd}$ .

**Figure 6-4. Voltage Waveforms, Propagation Delays for Standard CMOS Inputs**



(1) The greater between  $t_r$  and  $t_f$  is the same as  $t_t$ .

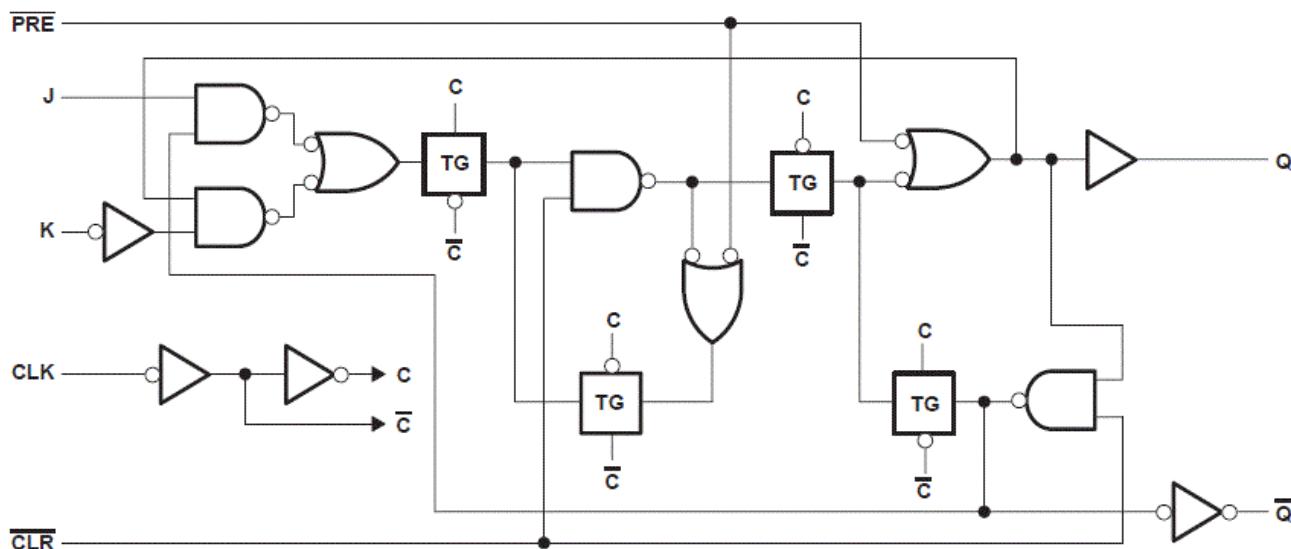
**Figure 6-5. Voltage Waveforms, Input and Output Transition Times for Standard CMOS Inputs**

## 7 Detailed Description

### 7.1 Overview

The SNx4HC112 devices contain two independent J-K negative-edge-triggered flip-flops. A low level at the preset ( $\overline{\text{PRE}}$ ) or clear ( $\overline{\text{CLR}}$ ) inputs sets or resets the outputs, regardless of the levels of the other inputs. When  $\overline{\text{PRE}}$  and  $\overline{\text{CLR}}$  are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock (CLK) pulse. Clock triggering occurs at a voltage level and is not directly related to the fall time of the CLK pulse. Following the hold-time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops perform as toggle flip-flops by tying J and K high.

### 7.2 Functional Block Diagram



### 7.3 Device Functional Modes

Table 7-1. Function Table

INPUTS					OUTPUTS	
$\overline{\text{PRE}}$	$\overline{\text{CLR}}$	CLK	J	K	Q	$\overline{Q}$
L	H	X	X	X	H	H
H	L	X	X	X	L	H
L	L	X	X	X	$H^{(1)}$	
H	H	↓	L	L	$Q_0$	$\overline{Q}_0$
H	H	↓	H	L	H	L
H	H	↓	L	H	L	H
H	H	↓	H	H	Toggle	
H	H	H	X	X	$Q_0$	$\overline{Q}_0$

(1) This configuration is non stable; that is, it does not persist when either  $\overline{\text{PRE}}$  or  $\overline{\text{CLR}}$  returns to its inactive (high) level.

## 8 Application and Implementation

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### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

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### 8.1 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. A  $0.1\mu F$  capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The  $0.1\mu F$  and  $1\mu F$  capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

### 8.2 Layout

#### 8.2.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices, inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or  $V_{CC}$ , whichever makes more sense for the logic function or is more convenient.

## 9 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

### 9.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com](http://ti.com). Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 9.2 Support Resources

[TI E2E™ support forums](#) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's [Terms of Use](#).

### 9.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

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### 9.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### 9.5 Glossary

#### [TI Glossary](#)

This glossary lists and explains terms, acronyms, and definitions.

## 10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

<b>Changes from Revision H (June 2022) to Revision I (September 2024)</b>	<b>Page</b>
• Updated the <i>Device Information</i> table to include package lead frame and body size.....	<a href="#">1</a>
• Changed $V_{CC}$ unit from: mA to: V in the <i>Absolute Maximum Ratings</i> section.....	<a href="#">3</a>

<b>Changes from Revision G (February 2022) to Revision H (June 2022)</b>	<b>Page</b>
• Junction-to-ambient thermal resistance values increased. D was 73 is now 117.2, N was 67 is now 89.1.....	<a href="#">4</a>

## 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

**PACKAGING INFORMATION**

Orderable part number	Status (1)	Material type (2)	Package   Pins	Package qty   Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
84088012A	Active	Production	LCCC (FK)   20	55   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	84088012A SNJ54HC 112FK
8408801EA	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8408801EA SNJ54HC112J
8408801FA	Active	Production	CFP (W)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8408801FA SNJ54HC112W
JM38510/65305BEA	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	JM38510/ 65305BEA
JM38510/65305BEA.A	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	JM38510/ 65305BEA
M38510/65305BEA	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	JM38510/ 65305BEA
SN54HC112J	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	SN54HC112J
SN54HC112J.A	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	SN54HC112J
SN74HC112D	Obsolete	Production	SOIC (D)   16	-	-	Call TI	Call TI	-40 to 85	HC112
SN74HC112DR	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 85	HC112
SN74HC112DR.A	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HC112
SN74HC112DRG4	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HC112
SN74HC112DRG4.A	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HC112
SN74HC112DT	Obsolete	Production	SOIC (D)   16	-	-	Call TI	Call TI	-40 to 85	HC112
SN74HC112N	Active	Production	PDIP (N)   16	25   TUBE	Yes	NIPDAU	N/A for Pkg Type	-40 to 85	SN74HC112N
SN74HC112N.A	Active	Production	PDIP (N)   16	25   TUBE	Yes	NIPDAU	N/A for Pkg Type	-40 to 85	SN74HC112N
SNJ54HC112FK	Active	Production	LCCC (FK)   20	55   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	84088012A SNJ54HC 112FK
SNJ54HC112FK.A	Active	Production	LCCC (FK)   20	55   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	84088012A SNJ54HC 112FK
SNJ54HC112J	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8408801EA SNJ54HC112J

Orderable part number	Status (1)	Material type (2)	Package   Pins	Package qty   Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
SNJ54HC112J.A	Active	Production	CDIP (J)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8408801EA SNJ54HC112J
<b>SNJ54HC112W</b>	Active	Production	CFP (W)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8408801FA SNJ54HC112W
SNJ54HC112W.A	Active	Production	CFP (W)   16	25   TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8408801FA SNJ54HC112W

<sup>(1)</sup> **Status:** For more details on status, see our [product life cycle](#).

<sup>(2)</sup> **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

<sup>(4)</sup> **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

**OTHER QUALIFIED VERSIONS OF SN54HC112, SN74HC112 :**

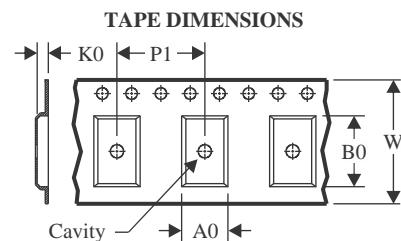
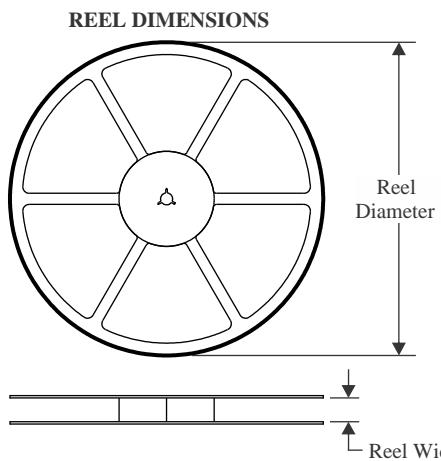
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- Catalog : [SN74HC112](#)

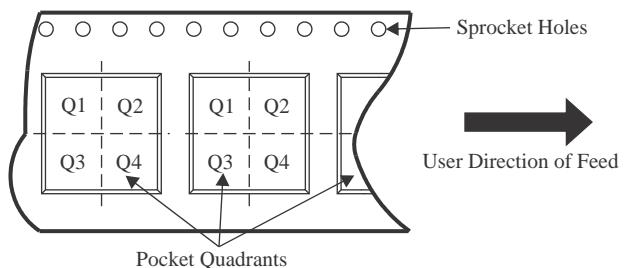
- Military : [SN54HC112](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Military - QML certified for Military and Defense Applications

**TAPE AND REEL INFORMATION**


A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HC112DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
SN74HC112DRG4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

**TAPE AND REEL BOX DIMENSIONS**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74HC112DR	SOIC	D	16	2500	353.0	353.0	32.0
SN74HC112DRG4	SOIC	D	16	2500	353.0	353.0	32.0

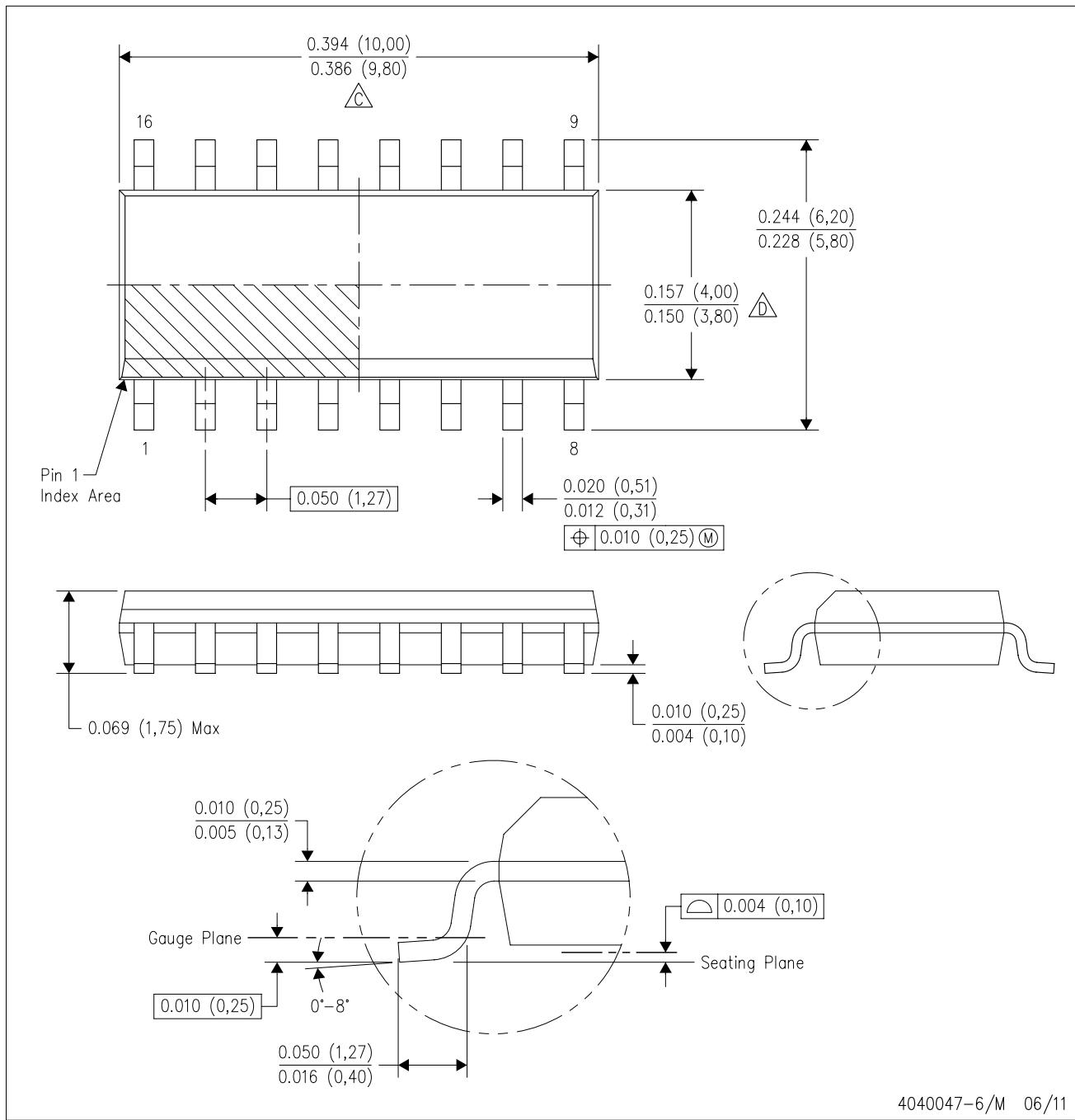
**TUBE**


\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T ( $\mu$ m)	B (mm)
84088012A	FK	LCCC	20	55	506.98	12.06	2030	NA
8408801FA	W	CFP	16	25	506.98	26.16	6220	NA
SN74HC112N	N	PDIP	16	25	506	13.97	11230	4.32
SN74HC112N	N	PDIP	16	25	506	13.97	11230	4.32
SN74HC112N.A	N	PDIP	16	25	506	13.97	11230	4.32
SN74HC112N.A	N	PDIP	16	25	506	13.97	11230	4.32
SNJ54HC112FK	FK	LCCC	20	55	506.98	12.06	2030	NA
SNJ54HC112FK.A	FK	LCCC	20	55	506.98	12.06	2030	NA
SNJ54HC112W	W	CFP	16	25	506.98	26.16	6220	NA
SNJ54HC112W.A	W	CFP	16	25	506.98	26.16	6220	NA

D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

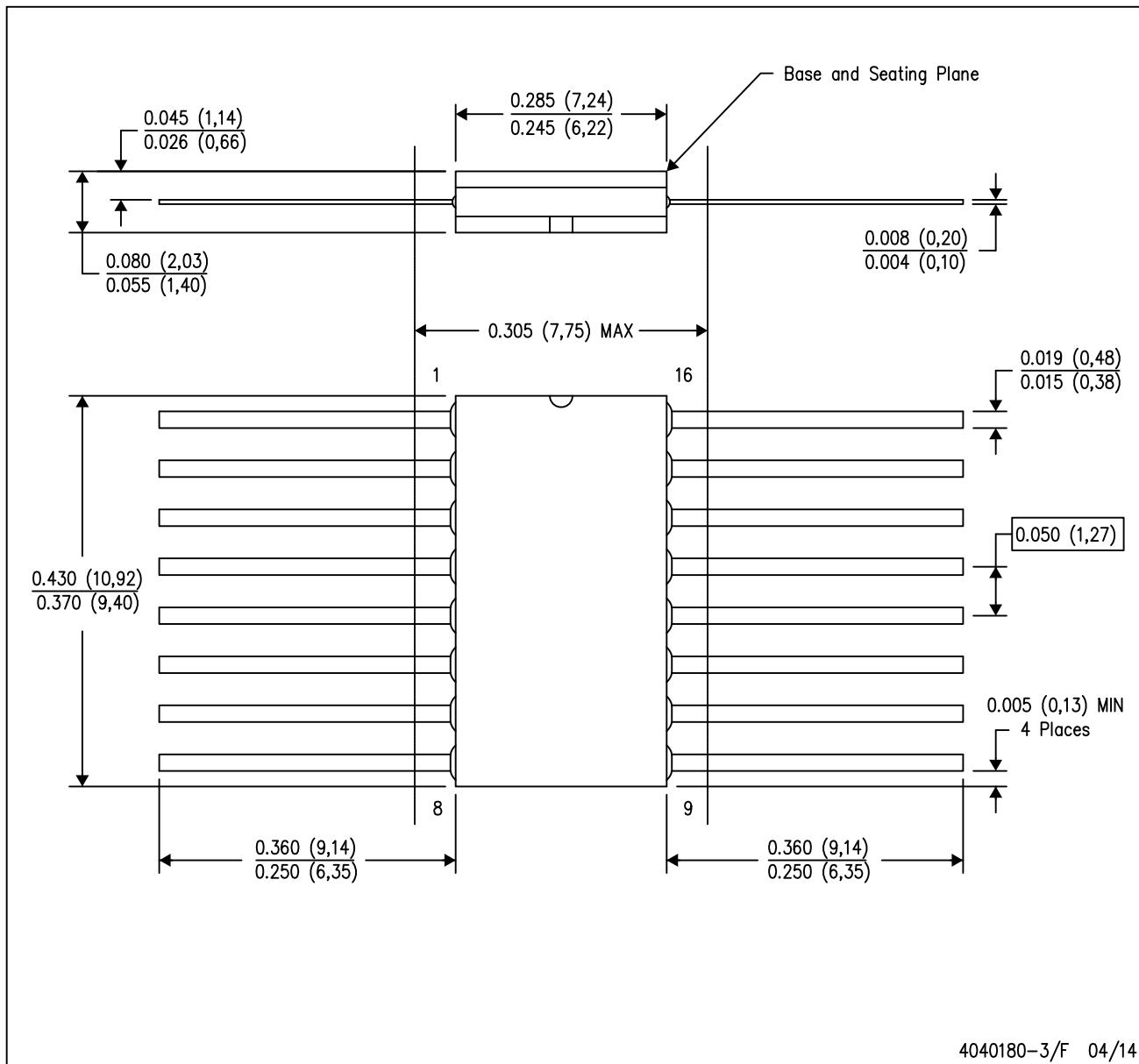
C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.

D. Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.

E. Reference JEDEC MS-012 variation AC.

W (R-GDFP-F16)

CERAMIC DUAL FLATPACK



4040180-3/F 04/14

NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only.
- E. Falls within MIL-STD 1835 GDFP2-F16

# GENERIC PACKAGE VIEW

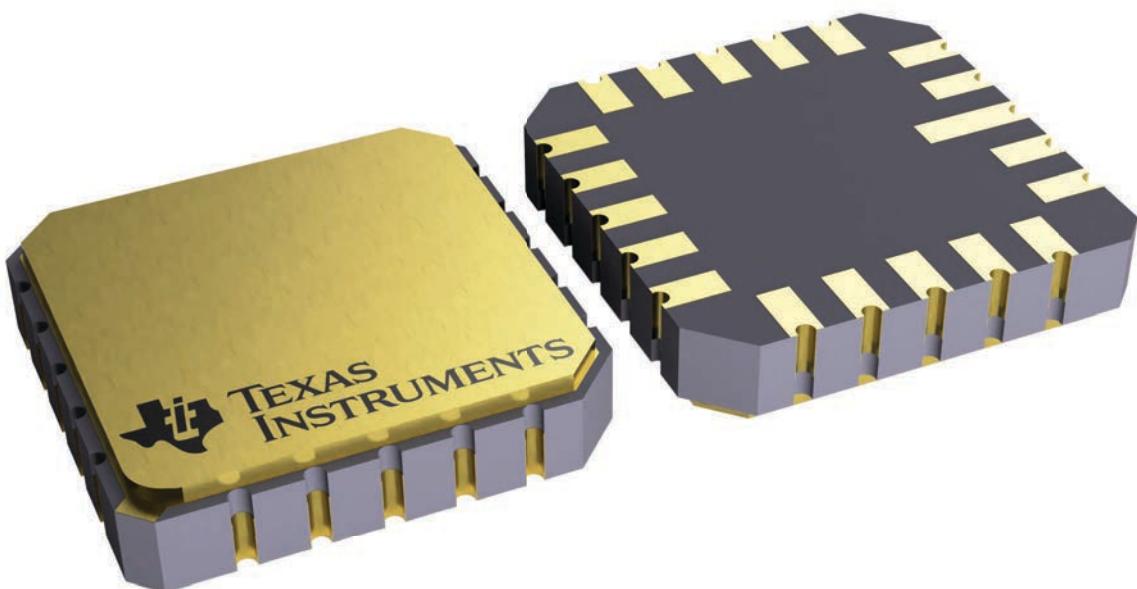
**FK 20**

**LCCC - 2.03 mm max height**

**8.89 x 8.89, 1.27 mm pitch**

**LEADLESS CERAMIC CHIP CARRIER**

This image is a representation of the package family, actual package may vary.  
Refer to the product data sheet for package details.

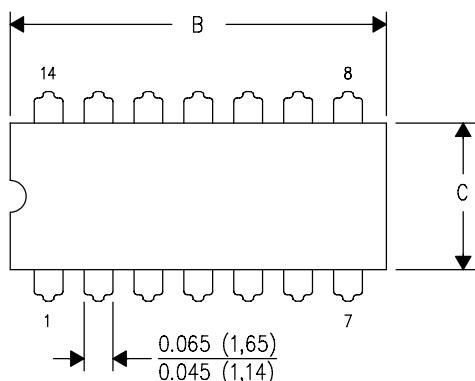


4229370VA\

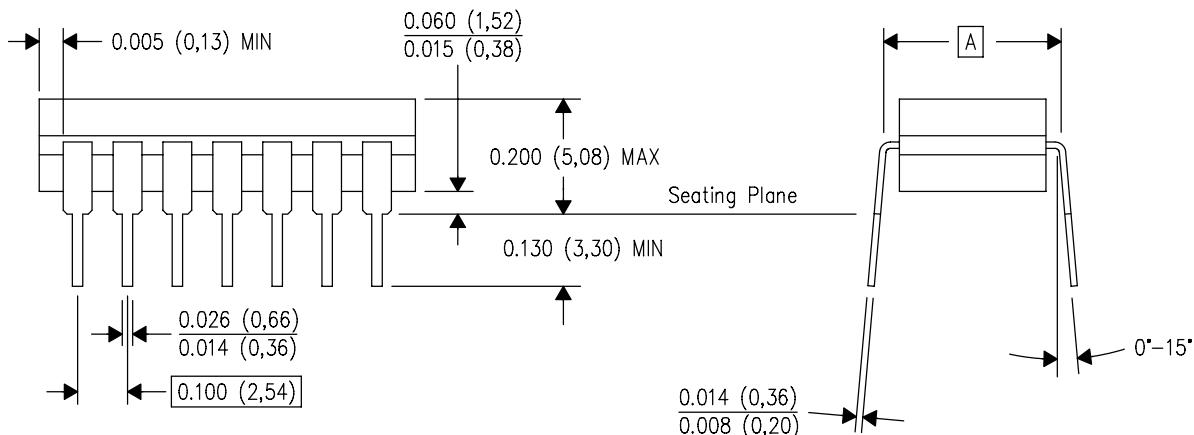
J (R-GDIP-T\*\*)

14 LEADS SHOWN

CERAMIC DUAL IN-LINE PACKAGE



PINS ** DIM	14	16	18	20
A	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC
B MAX	0.785 (19,94)	.840 (21,34)	0.960 (24,38)	1.060 (26,92)
B MIN	—	—	—	—
C MAX	0.300 (7,62)	0.300 (7,62)	0.310 (7,87)	0.300 (7,62)
C MIN	0.245 (6,22)	0.245 (6,22)	0.220 (5,59)	0.245 (6,22)



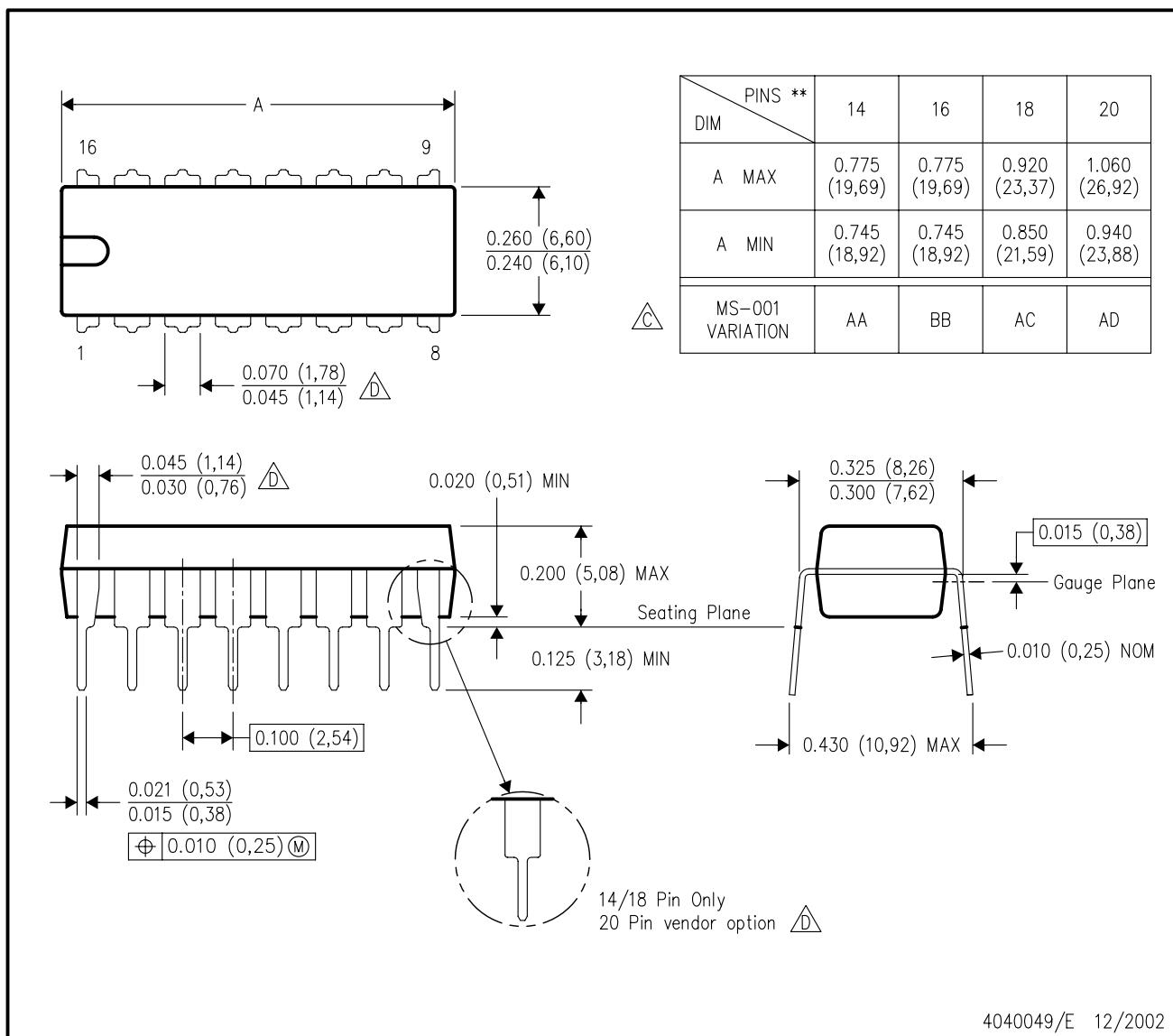
4040083/F 03/03

NOTES: A. All linear dimensions are in inches (millimeters).  
B. This drawing is subject to change without notice.  
C. This package is hermetically sealed with a ceramic lid using glass frit.  
D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.  
E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

## N (R-PDIP-T\*\*)

16 PINS SHOWN

## PLASTIC DUAL-IN-LINE PACKAGE



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Last updated 10/2025